

July 22, 2021

Ms. Nawal Cotran Director, Quality and Reliability Integra Technologies Silicon Valley, LLC 1635 McCarthy Blvd. Milpitas, CA 95035

Dear Ms. Cotran:

Re: QML Laboratory Suitability Status; MIL-STD-883; FSC 5962; VQC-20-035107; Yu. CN: 072244.

Integra Technologies Silicon Valley, LLC (ISV) has demonstrated to the DLA Land and Maritime compliance with MIL-STD-883, the test standard for integrated circuits. ISV is granted laboratory suitability, effective on the date of this letter, for the facilities, test methods and conditions shown on the enclosure. All testing must be performed in accordance with MIL-PRF-38535 and MIL-STD-883 test methods.

This letter is issued in conjunction with the QML certification letter DLA Land and Maritime-VQC-20-035108 and supersedes the previous laboratory suitability letter DLA Land and Maritime-VQC-17-013092.

ISV shall notify the qualifying activity immediately after learning of a potential issuance of a GIDEP alert, problem advisory or major quality/reliability problem on the military products utilizing the test methods on the attached enclosure. Failure to provide prior notification may be grounds for removal from DLA Land and Maritime's laboratory suitability.

This laboratory suitability is subject to the policies, procedures, and conditions of the Defense Standardization Program, as published in the manual DoD 4120.24-M, SD-6.

This laboratory suitability is valid until terminated by written notice from DLA Land and Maritime. If warranted, it may be withdrawn by DLA Land and Maritime at any time. Each of these facilities is subject to an audit by DLA Land and Maritime with a minimum notice.

If you have any questions, please contact Mr. Shing Yu at (614) 692-0588.

Sincerely,

MICHAEL S. ADAMS Chief Custom Devices Branch

TEST	METHOD/CONDITION	Integra- ISV	Integra-ABQ Integra-ICT	SUBCONTRACTORS
Temperature Cycling	1010 C	X		Hi-Reliability Microelectronics
Seal	1014 A ₂ , C ₁	X		Hi-Reliability Microelectronics
Burn-in	1015 A-E	X		Hi-Reliability Microelectronics ISE Labs
Constant Acceleration	2001 D-E	Х		Hi-Reliability Microelectronics
Solderability	2003 Test A		ICT	Hi-Reliability Microelectronics Six Sigma
External Visual	2009	Х		
Internal Visual	2010 А-В	Х	ABQ	
Bond Strength	2011 D	Х	ABQ	
Radiography	2012		ABQ (digital)	NDT (film)
Resistance to Solvents	2015			Hi-Reliability Microelectronics
Die Shear Strength	2019	Х	ABQ	Hi-Reliability Microelectronics
Particle Impact Noise Detection (PIND)	2020 А-В			NDT; Hi-Reliability Microelectronics
Nondestructive Bond Pull	2023	X		
Lid Torque	2024	Х		
Substrate Attach Strength	2027	Х		
Electrical Test	See Note 1		ICT	

Note 1: Integra's electrical test systems are certified in compliance with MIL-STD-883 paragraph 4.5 as applicable. Integra's system is suitable to perform electrical test over military case temperature (Tcase) of 25°, 125°, and -55° C. Electrical Test suitability does not cover individual test programs. It is the responsibility of Integra to obtain a record of customer approval stating that the hardware/software integration, including resolution and accuracy are adequate to meet the forcing and measurement conditions required, for the specified device type.

Facilities Information:

Hi-Reliability Microelectronics 1804 McCarthy Blvd Milpitas, CA 95053

Integra-ABQ 10401 Research Rd SE Albuquerque, NM 87123-3423

Integra-ICT 3450 N Rock Rd Wichita, KS 67266

ISE Labs 46800 Bayside Parkway Fremont, CA 94538-6592 NDT 240 East Caribbean Dr. Sunnyvale, CA 94089

Six Sigma 905 Montague Expressway Milpitas, CA 95035